

MODELING, SIMULATION AND DESIGN

J.W. Bandler

OSA-96-MT-12-V

June 10, 1996

© Optimization Systems Associates Inc. 1996

No part of this document, related documentation and data may be acquired, copied, reproduced, duplicated, executed, lent, disclosed, circulated, translated, transcribed or entered in any form into any machine without written permission from Optimization Systems Associates Inc. Neither Optimization Systems Associates Inc. nor any other person, company, agency or institution make any warranty, express or implied, or assume any legal responsibility for the accuracy, completeness or usefulness of the material presented herein, or represent that its use would not infringe upon privately owned rights. This title page and original cover may not be separated from the contents of this document. It is understood that full acknowledgement of source will accompany any disclosure or publication of the results of use of this material by any person or party.

Effective CAD: a Dilemma of Models!

a panel session at the 1996 IEEE MTT-S International Microwave Symposium/Exhibition, San Francisco, CA, June 19, 1996

Time: 12:15 - 1:35 pm

Location: Moscone Convention Center

Sponsor: MTT-1 Computer-Aided Design

Organizer: John W. Bandler, OSA, Canada

Panelists: Fritz Arndt, Univ. Bremen, Germany
John Bandler, OSA, Canada
Mike Golio, Motorola, USA
Anthony M. Pavio, Motorola, USA
Roberto Sorrentino, Univ. Perugia, Italy
Chris Snowden, University of Leeds, UK

Abstract

Device and circuit modeling methodologies aimed at low cost design and manufacture are addressed, including automated performance-, and yield-driven design optimization of microwave and millimeter-wave circuits with accurate EM simulations invoked within the optimization loop. Concepts such as

the Hybrid Mode Matching/Circuit Theory approach,

the classical Adjoint Network Method,

the Feasible Adjoint Sensitivity Technique,

Hybrid Visualization-aided EM Modeling,

and the recent Space Mapping technique

promise to accelerate design optimization exploiting EM/physical simulators. As a result, CAD and modeling of engineering devices, circuits and systems will reach a level of precision and computational efficiency previously undreamed of. These concepts are founded on empirical engineering modeling, circuit theory and field theory, which embody expert knowledge accumulated over many years.

Issues

why is electromagnetic optimization necessary?

a dilemma: physical, physics-based or circuit modeling?

is statistical device modeling necessary?

tradeoffs: cut and try, visualization and user-friendliness

the eternal issue: classical or numerical design
methodologies

MODELING, SIMULATION AND DESIGN

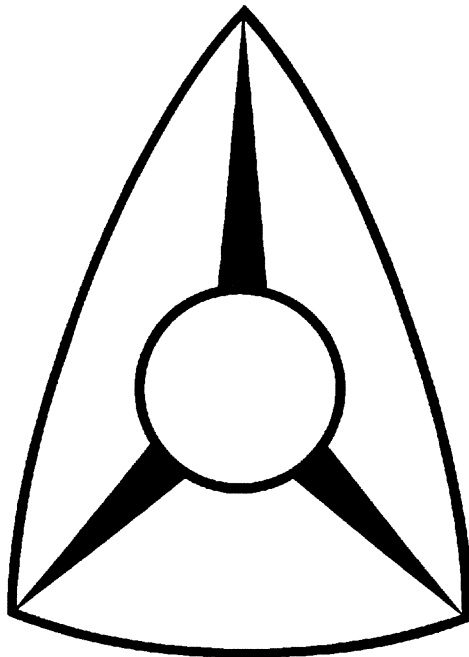
J.W. Bandler

Optimization Systems Associates Inc.

P.O. Box 8083, Dundas, Ontario

Canada L9H 5E7

Email osa@osacad.com URL <http://www.osacad.com>



presented at

Panel Session on Effective CAD: A Dilemma of Models!
IEEE MTT-S Symposium/Exhibition, San Francisco, CA, June 19, 1996



Modeling, Simulation and Design

$$Ax = b$$

simulation

(1) given A and x find b

easy

(2) forward problem:

given A and b find x

more difficult

optimization

(3) design problem:

given b and specs on x find some of A

difficult

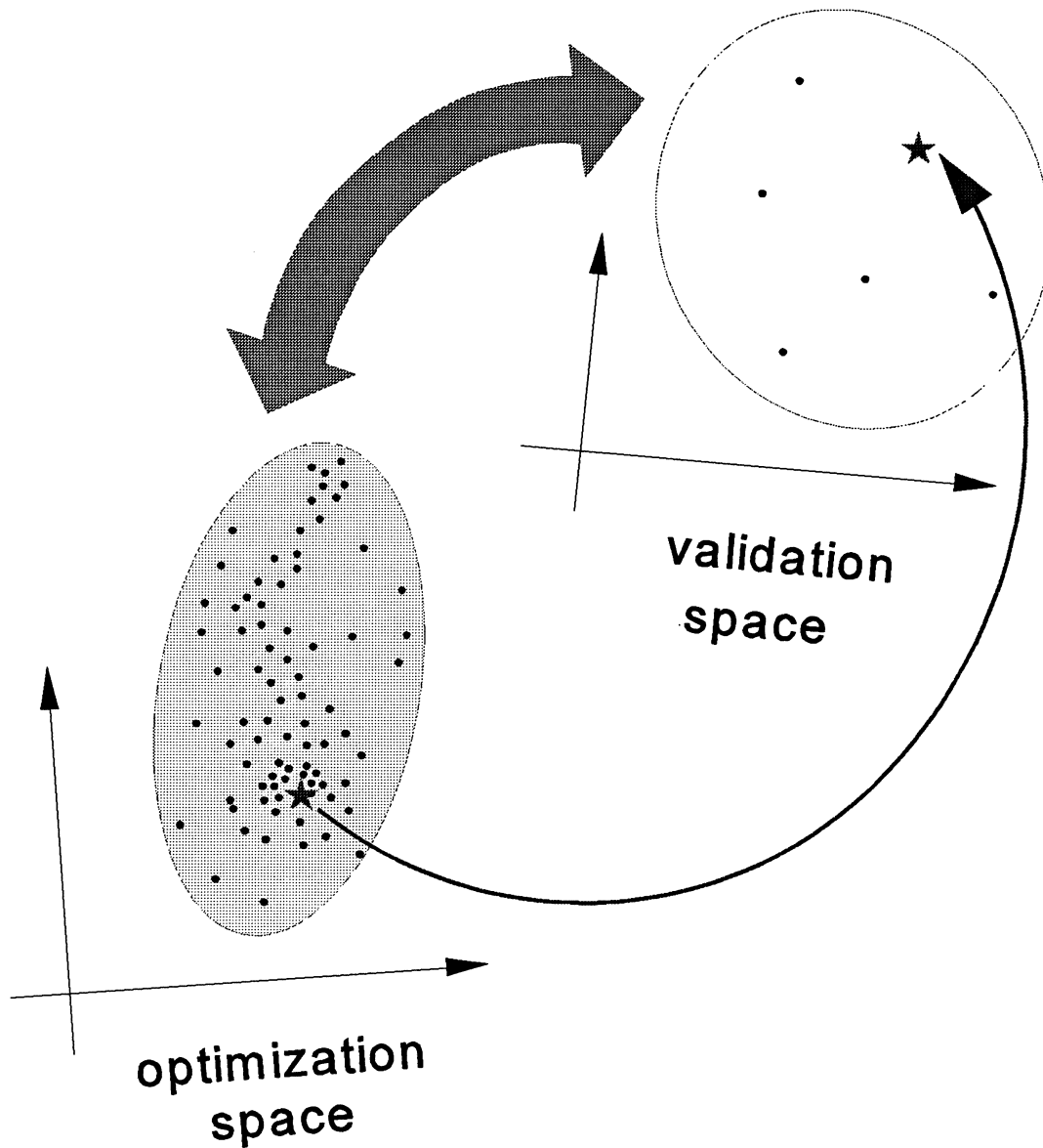
(4) inverse problem:

given x and b find A

very difficult



Space Mapping™
(Bandler et al., 1994)





FAST - The Feasible Adjoint Sensitivity Technique

performs adjoint sensitivities

retains most of the efficiency and accuracy of the EAST
(exact adjoint sensitivity technique)

accommodates the simplicity of the conventional
perturbation method, which we name PAST (perturbation
approximate sensitivity technique)

directly applicable to both the node/port formulation and the
state variable formulation

suitable for implementation within the framework of general
purpose software

extends to the computation of Jacobians for high speed HB
simulation

the features of FAST and its Jacobian extensions are
illustrated by a mixer example and a frequency doubler
example



Gradient Analysis Using FAST

the harmonic balance equation (split real-imaginary)

$$F(\boldsymbol{\phi}, V) = \mathbf{0}$$

the output voltage is computed as

$$V_{out} = \mathbf{e}^T V$$

an approximate sensitivity of the output voltage is

$$\partial V_{out} / \partial \boldsymbol{\phi} \approx -\hat{V}^T F(\boldsymbol{\phi} + \Delta \boldsymbol{\phi}, V_{solution}) / \Delta \boldsymbol{\phi}$$

adjoint voltages \hat{V} are obtained from solving the linear system

$$\mathbf{J}^T \hat{V} = \mathbf{e}$$

where \mathbf{J} is the Jacobian matrix at the solution



Comparison of FAST with PAST

consider 10 design variables in a nonlinear circuit

PAST analysis

the circuit has to be perturbed 10 times
10 nonlinear circuits have to be solved

FAST analysis

the circuit has to be perturbed 10 times
no additional nonlinear circuits have to be solved
only 10 errors need to be evaluated

the best possible situation for PAST is that all 10 simulations
use the same Jacobian and all converge in one iteration

FAST always requires less computation than that of the best
possible situation of PAST since error evaluation takes a
fraction of the time needed for simulation

FAST is more accurate than PAST



Comparison of FAST with EAST

EAST

commonly accepted as the most powerful tool
a need to keep track of variable locations
expensive to implement

FAST

no need to keep track of variable locations
only the output port has to be identified
implementable in general CAD programs